

<b>Notice of References Cited</b>	Application/Control No. 10/779,503	Applicant(s)/Patent Under Reexamination JAMES WEBB ET AL.	
	Examiner Charles A Harkness	Art Unit 2183	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,751,985	05-1998	Shen et al.	712/218
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Popescu, V.; Schultz, M., Spracklen, J.; Gibson, G.; Lightner, B.; Isaman, D. IEEE Micro, vol. 11 Issue: 3, Jun. 1991. Page(s): 10-13, 63-73.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.